TRANSMITTAL OI	Docket No. 3829.01										
In Re Application Of: Charles E. BRYSON, III et al.											
Serial No.	Filing Date	Examiner		Group Art Unit							
10/618,078	July 11, 2003	unknown		2881							
Title: ELECTRON TRANSMISSIVE WINDOW USABLE WITH HIGH PRESSURE ELECTRON SPECTROMETRY NOV 2 8 2003 8											
Address to: Assistant Commissioner for Patents Washington, D.C. 20231											
37 CFR 1.97(b)											
1. A The Information Disclosure Statement submitted herewith is being filed within three months of the filing of a national application other than a continued prosecution application under 37 CFR 1.53(d); within three months of the date of entry of the national stage as set forth in 37 CFR 1.491 in an international application; before the mailing of a first Office Action on the merits, or before the mailing of a first Office Action after the filing of a request for continued examination under 37 CFR 1.114. 37 CFR 1.97(c)											
2. The Information Disclosure Statement submitted herewith is being filed after the period specified in 37 CFR 1.97(b), provided that the Information Disclosure Statement is filed before the mailing date of a Final Action under 37 CFR 1.113, a Notice of Allowance under 37 CFR 1.311, or an Action that otherwise closes prosecution in the application, and is accompanied by one of:											
☐ the statement specified in 37 CFR 1.97(e);											
	OR										
☐ the fee set	t forth in 37 CFR 1.17(p).			•							

TRANSMITTAL OF INFORMATION DISCLOSURE STATEMENT Docket No. 3829.01 (Under 37 CFR 1.97(b) or 1.97(c)) In Re Application: Charles E. BRYSON, III et al. Examiner **Group Art Unit** Filing Date Serial No. 2881 July 11, 2003 unknown 10/618,078 ELECTRON TRANSMISSIVE WINDOW USABLE WITH HIGH PRESSURE ELECTRON NOV 2 8 2003 Payment of Fee (Only complete if Applicant elects to pay the fee set forth in 37 CFR 1.17(p)) A check in the amount of is attached. ∑ The Assistant Commissioner is hereby authorized to charge and credit Deposit Account No. 50-0636 as described below. A duplicate copy of this sheet is enclosed. Charge the amount of Credit any overpayment. X Charge any additional fee required. Certificate of Mailing by First Class Mail Certificate of Transmission by Facsimile* I certify that this document and authorization to charge deposit I certify that this document and fee is being deposited with the U.S. Postal Service account is being facsimile transmitted to the United States Nov. 11, 2003 as first class mail under 37 C.F.R. 1.8 and is Patent and Trademark Office (F addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231. (Date) Signature of Person Mailing Correspondence Signature Ingrid C. Mallory Typed or Printed Name of Person Mailing Certificate Typed or Printed Name of Person Signing Certificate *This certificate may only be used I paying by denost account. Dated: November 11, 2003 Signature Charles S. Guenzer, Reg. No. 30,640 (650) 566-8040 Mailing Address: Law Offices of Charles Guenzer 2211 Park Boulevard P.O. Box 60729 Palo Alto, CA 94306 CC:

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U.S. Department of Commerce, Patent and Traction of Commerce, Pate					Docket N	Docket No.: 3829.01					
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	AN	L. E. Trimble 3200-3203 pp.		rane fragility: fact or illusi	ion?", J. Vac. Sci.	Technol. B, vol	l. 10, no. 6, No	v/Dec 1992			
	AQ	Micromechanics and Microengineering" vol. 12, 2002, 475-478 pp. N. J. Lanno et al., "Measurement of the permeability of thin films", Review of Scientific Instruments", vol. 70, 4, April 1999, 2072-2073 pp. Jinling Yang et al., "Fracture properties of LPCVD silicon nitride thin films from the load-deflection of long membranes", Sensors and Actuators A, vol. 97, no. 98, 2002, 520-526 pp.									
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